

## INTERNATIONAL SEARCH REPORT

International Application No

PCT/FR 02/03422

**A. CLASSIFICATION OF SUBJECT MATTER**  
 IPC 7 H01L21/762

According to International Patent Classification (IPC) or to both national classification and IPC

**B. FIELDS SEARCHED**

Minimum documentation searched (classification system followed by classification symbols)

IPC 7 H01L

Documentation searched other than minimum documentation to the extent that such documents are included in the fields searched

Electronic data base consulted during the international search (name of data base and, where practical, search terms used)

EPO-Internal, WPI Data, PAJ, INSPEC, IBM-TDB

**C. DOCUMENTS CONSIDERED TO BE RELEVANT**

Category *	Citation of document, with indication, where appropriate, of the relevant passages	Relevant to claim No.
X	YUN C H ET AL: "Thermal and mechanical separations of silicon layers from hydrogen pattern-implanted wafers" JOURNAL OF ELECTRONIC MATERIALS, AUG. 2001, TMS;IEEE, USA, vol. 30, no. 8, pages 960-964, XP008005517 ISSN: 0361-5235 abstract; figure 1	1-5, 7, 13, 15, 16
Y	---	6, 8-12, 14
	--- -/--	

☒ Further documents are listed in the continuation of box C.

☒ Patent family members are listed in annex.

\* Special categories of cited documents:

\*A\* document defining the general state of the art which is not considered to be of particular relevance

\*E\* earlier document but published on or after the international filing date

\*L\* document which may throw doubts on priority claim(s) or which is cited to establish the publication date of another citation or other special reason (as specified)

\*O\* document referring to an oral disclosure, use, exhibition or other means

\*P\* document published prior to the international filing date but later than the priority date claimed

\*T\* later document published after the international filing date or priority date and not in conflict with the application but cited to understand the principle or theory underlying the invention

\*X\* document of particular relevance; the claimed invention cannot be considered novel or cannot be considered to involve an inventive step when the document is taken alone

\*Y\* document of particular relevance; the claimed invention cannot be considered to involve an inventive step when the document is combined with one or more other such documents, such combination being obvious to a person skilled in the art.

\*&\* document member of the same patent family

Date of the actual completion of the international search

15 January 2003

Date of mailing of the international search report

22/01/2003

Name and mailing address of the ISA

European Patent Office, P.B. 5818 Patentlaan 2  
 NL - 2280 HV Rijswijk  
 Tel. (+31-70) 340-2040, Tx. 31 651 epo nl,  
 Fax: (+31-70) 340-3016

Authorized officer

Wirner, C

## INTERNATIONAL SEARCH REPORT

International Application No

PCT/FR 02/03422

## C.(Continuation) DOCUMENTS CONSIDERED TO BE RELEVANT

Category *	Citation of document, with indication, where appropriate, of the relevant passages	Relevant to claim No.
X	YUN C H ET AL: "Fractional implantation area effects on patterned ion-cut silicon layer transfer" SOI CONFERENCE, 1999. PROCEEDINGS. 1999 IEEE INTERNATIONAL ROHNERT PARK, CA, USA 4-7 OCT. 1999, PISCATAWAY, NJ, USA, IEEE, US, 4 October 1999 (1999-10-04), pages 129-130, XP010370243 ISBN: 0-7803-5456-7 abstract; figure 1 ----	1-5,7, 13,15,16
X	PATENT ABSTRACTS OF JAPAN vol. 1999, no. 05, 31 May 1999 (1999-05-31) -& JP 11 045862 A (DENSO CORP), 16 February 1999 (1999-02-16) abstract; figures ----	1,3-5,7, 13,15,16
X	PATENT ABSTRACTS OF JAPAN vol. 1999, no. 08, 30 June 1999 (1999-06-30) -& JP 11 074208 A (DENSO CORP), 16 March 1999 (1999-03-16) abstract; figures ----	1-5,7, 13,15,16
Y	US 6 054 370 A (DOYLE BRIAN S) 25 April 2000 (2000-04-25) abstract; claims; figures 3-7,10 ----	6,8,9
Y	FR 2 797 347 A (COMMISSARIAT ENERGIE ATOMIQUE) 9 February 2001 (2001-02-09) abstract; claims; figures ----	10-12,14
A	EP 0 938 129 A (CANON KK) 25 August 1999 (1999-08-25) abstract; claims; figures 1C,6A -----	1,6,8-11

## INTERNATIONAL SEARCH REPORT

International Application No

PCT/FR 02/03422

Patent document cited in search report		Publication date	Patent family member(s)		Publication date
JP 11045862	A	16-02-1999	NONE		
JP 11074208	A	16-03-1999	NONE		
US 6054370	A	25-04-2000	NONE		
FR 2797347	A	09-02-2001	FR	2797347 A1	09-02-2001
			EP	1203403 A1	08-05-2002
			WO	0111667 A1	15-02-2001
			TW	457565 B	01-10-2001
EP 0938129	A	25-08-1999	CN	1228607 A	15-09-1999
			EP	0938129 A1	25-08-1999
			JP	3031904 B2	10-04-2000
			JP	11317509 A	16-11-1999
			SG	81964 A1	24-07-2001
			TW	437078 B	28-05-2001
			US	2002093047 A1	18-07-2002
			US	6342433 B1	29-01-2002